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Claims

1. A hemifumarate crystal of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°.

2. A hemifumarate anhydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°.

3. A hemifumarate X-hydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°.

4. A process for preparing a hemifumarate X-hydrate of a compound of formula 5 (I):

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characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, to obtain said hemifumarate X-hydrate.

5. A process for preparing a hemifumarate anhydrate of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of treating a hemifumarate crystal form of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, to obtain said hydrate.

6. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

10 characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) 6.6° and 8.5°, to obtain said hydrate.

7. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

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characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, wherein said hemifumarate anhydrate is obtained by treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°.

8. A hemifumarate crystal of a compound of formula (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°.

9. A hemifumarate crystal of a compound of formula (I):

containing acetone and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4° , 10.4° , 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

10. A hemifumarate crystal of a compound of formula (I):

containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4° , 10.4° , 10.7° and 12.1° measured by X-ray diffractometry using

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11. A hemifumarate crystal of a compound of formula (I):

containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4° , 10.4° , 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

12. (Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

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showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-Kα radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°, to obtain said hydrate.

13. (Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

containing acetone and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4° , 10.4° , 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation, said process comprising the step of treating a hemifumarate crystal of the

compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°, to obtain said hydrate.

14. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

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containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-K\alpha radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°, to obtain said hydrate.

15. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4° , 10.4° , 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-

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ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°, to obtain said hydrate.

16. A process for preparing a hemifumarate anhydrate of a compound of formula(I):

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characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of obtaining said anhydrate by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.

17. A process for preparing a hemifumarate X-hydrate of a compound of formula

10 (I):

characterized by 2-theta angle positions in the powder X-ray diffraction pattern of showing strong X-ray diffraction peaks at diffraction angles $2\theta = 7.1^{\circ}$ and 14.2° , said process comprising the step of obtaining said hydrate by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.

18. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

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characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, wherein said anhydrate is obtained by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.